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31 July 1964 GN:bb:366 (997-112)

STATINTL

TRIP REPORT

STATINTL Purpose: To Evaluate Microdensitometers
STATINTL Persons
STATINTL Contacted:

STATINTL STATINTL

STATINTL STATINTL During the day of 23 July, a series of tests were conducted on a Model III Microdensitometer. The instrument was operated by

STATINTL indicated that entered the field of microdensitometry in 1956 with the intention of making an instrument for in-house purposes.

The Model III is a modified version of the original instrument.

The instrument has a scanning capability in only one direction. A Leitz stage is used to obtain sample rotation. The stage design is such that continuous scanning is limited to one inch in the x direction. Upon removal of the Leitz stage an eight inch scan can be accomplished, but rotation is not possible. The mensuration accuracy, as stated by is $\pm 15 \,\mu$. The basic price for the Model III microdensitometer is A digitized system has recently been developed and is available at an additional cost.

A lower cost instrument, the Model V, has been developed for commercial use. The Model V uses Quanta-log electronics, a Leitz stage and

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Memorandum by

MM:bb:282, 22 June 1964.

Declass Review by NIMA/DOD

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10 August 1964 Trip Report GN:bb:366 (997) Page 2 STATINTLeitz optics. The instrument has the same scan limitation as the Model III. $\pm 2-1/2 \mu$. The overall cost is Its mensuration accuracy is estimated to ice could be reduced considerably We were informed that the if a number of instruments were purchased. There are no provisions on either the Model III or the Model V for handling roll film. A mirror system is used for viewing when the instrument is not in the scanning operation. An automatic focusing device has been designed for use with their Model III microdensitometer. At the time of the visit the focusing device was under modification and would not be operational until the first part of August. Tentative arrangements were made for us to return when the system is oper-This will also give us an opportunity to discuss a number of items where information was initially lacking and which is custant MTL STATINT checking. indicated that hopes to introduce a micropartiff STATINTLtometer in the near future which would be designed specifically for commercial STATINTLuse. Te indicated the instrument would consist of a Comps: PATINTL optics. The instrument would be assembled electronics and STATINTL and special features would be available. STATINTL

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Ext. 547